

<b>Notice of References Cited</b>	Application/Control No. 10/083,203	Applicant(s)/Patent Under Reexamination WU, DAVID CHAOHUA	
	Examiner BRIAN P. YENKE	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-2003/0162517	08-2003	Wu, David ChaoHua	455/237.1
X	B	US-6,295,362	09-2001	Zhang, Qin	381/2
X	C	US-6,259,482	07-2001	Easley et al.	348/485
X	D	US-6,281,813	08-2001	Vierthaler et al.	341/50
X	E	US-6,037,993	03-2000	Easley, Matthew Frank	348/485
X	F	US-6,122,380	09-2000	Pedlow, Jr., Leo Mark	381/2
X	G	US-6,492,913	12-2002	Vierthaler et al.	341/50
X	H	US-6,664,849	12-2003	Taura et al.	329/315
X	I	US-2003/0091194	05-2003	Teichmann et al.	381/2
X	J	US-6,535,608	03-2003	Taira, Masaaki	381/2
X	K	US-6,552,753	04-2003	Zhurbinskiy et al.	348/738
X	L	US-6,118,879	09-2000	Hanna, Christopher M.	381/106
X	M	US-6,608,902	08-2003	Jackson et al.	381/1

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.